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**Test sieves — Technical requirements and testing —  
Part 1: Test sieves of metal wire cloth**

**Official edition**

**CSM**

**Bishkek**

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## Foreword

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The procedures used to develop this document and those intended for its further maintenance are described in the ISO/IEC Directives, Part 1. In particular the different approval criteria needed for the different types of ISO documents should be noted. This document was drafted in accordance with the editorial rules of the ISO/IEC Directives, Part 2 (see [www.iso.org/directives](http://www.iso.org/directives)).

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For an explanation on the meaning of ISO specific terms and expressions related to conformity assessment, as well as information about ISO's adherence to the WTO principles in the Technical Barriers to Trade (TBT) see the following URL: [Foreword - Supplementary information](#)

The committee responsible for this document is ISO/TC 24, *Particle characterization including sieving*, Subcommittee SC 8, *Test sieves, sieving and industrial screens*.

This fifth edition cancels and replaces the fourth edition (ISO 3310-1:2000), which has been technically revised. It also incorporates the Technical Corrigendum ISO 3310-1:2000/Cor 1:2004.

ISO 3310 consists of the following parts, under the general title *Test sieves — Technical requirements and testing*:

- *Part 1: Test sieves of metal wire cloth*
- *Part 2: Test sieves of perforated metal plate*
- *Part 3: Test sieves of electroformed sheets*

## **Introduction**

As the accuracy of test sieving depends on the dimensional accuracy of the test sieve openings, it is considered necessary in this part of ISO 3310 to keep the maximum permissible error on the apertures in metal wire cloth as close as possible.

Requirements other than maximum permissible errors on the apertures, such as requirements for the wire diameter, have not been limited more closely than necessary, since the influence of these criteria on test sieving is of minor importance, and excessively strict requirements may make manufacturing unnecessarily difficult.

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